Electronic Supplementary Material (ESI) for Soft Matter.

Supporting Information for:

Creation of liquid-crystal periodic zigzags by surface treatment and thermal annealing

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Figure S1

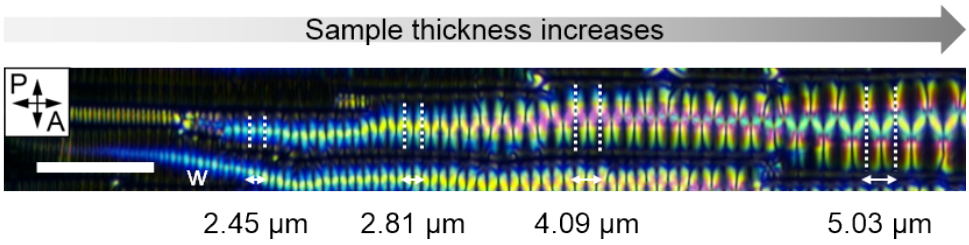

Fig. S1 DRLM images of the zigzag structures as increasing sample thickness. The scale bar is 20 μm.

Figure S2

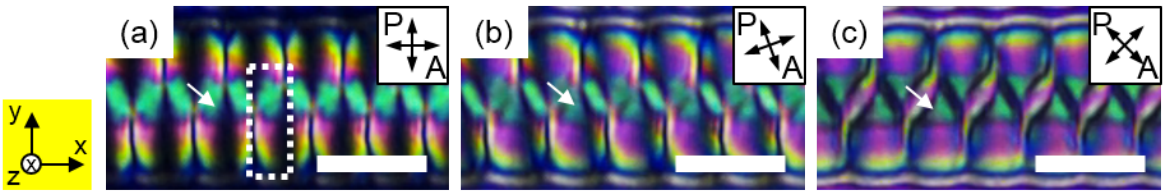

Fig. S2 DRLM images of the zigzag structure as rotating crossed polarizers at (a) 0°, (b) 20°, and (c) 45°. The scale bar is 10 μm.

Figure S3

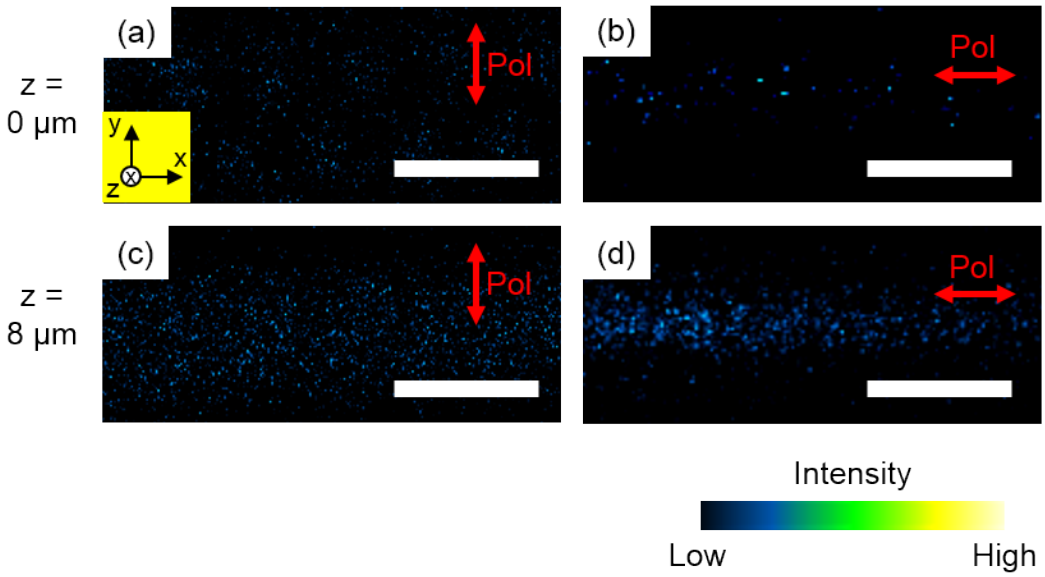

Fig. S3 The fluorescent intensities in LSFCM images at (a and b) z = 0 µm and (c and d) z = 8 µm. The scale bar is 10 µm.

Figure S4

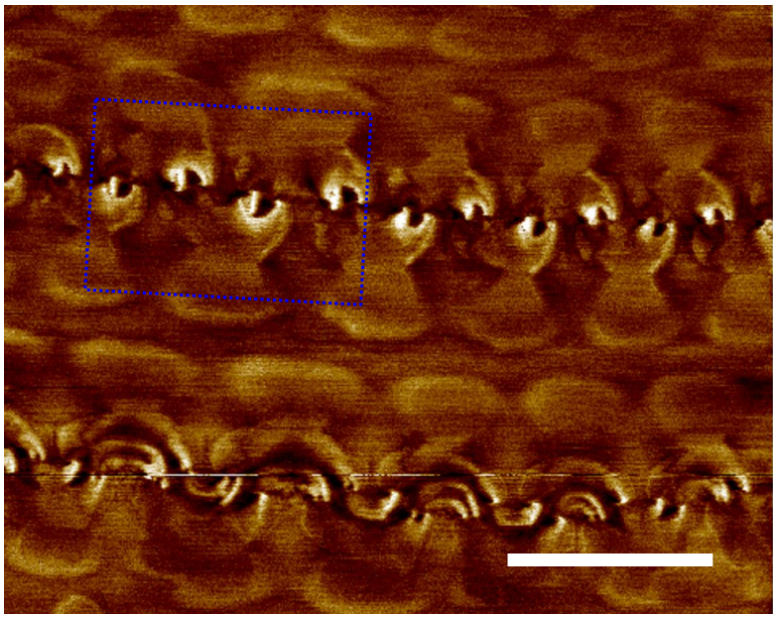

Fig. S4 The AFM phase image of the zigzag structure. The blue box is the same area shown in the Figure 4(a). The scale bare is 10 μm.

Figure S5

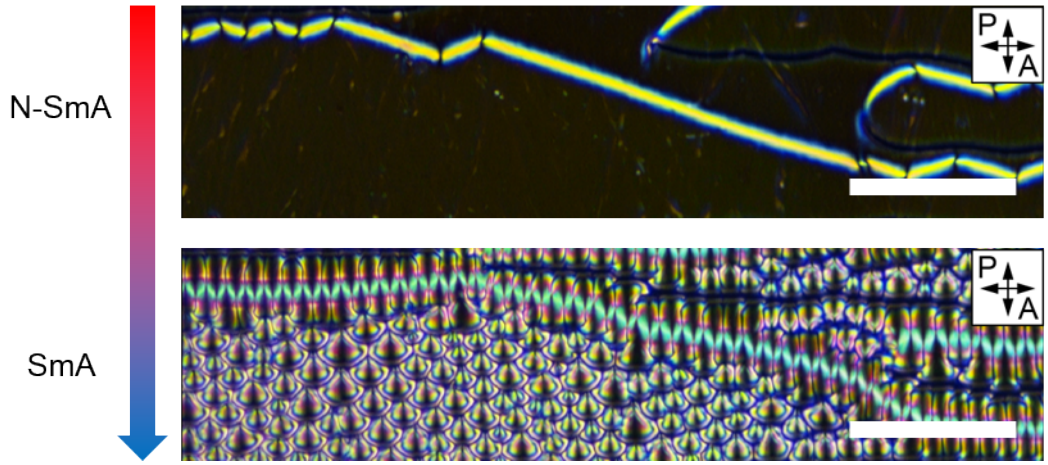

Fig. S5 Structural transition behaviour of the zigzag disclination lines upon cooling from N-SmA transition to SmA phase. The scale bare is 50 μm.

Figure S6

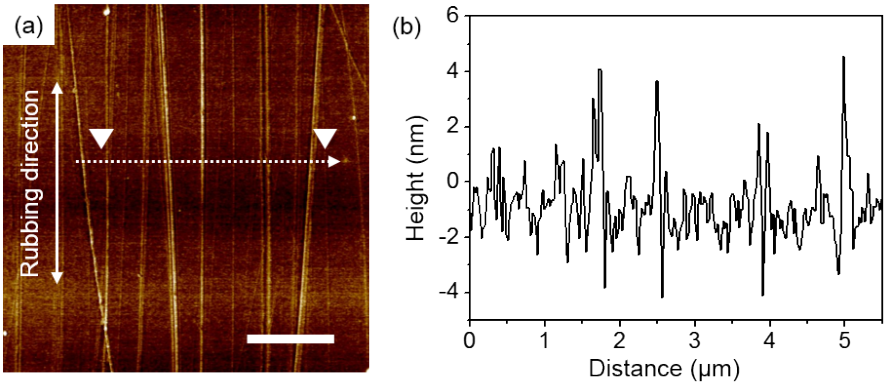

Fig. S6 A AFM study of the rubbed PI-coated Si substrate. (a) The AFM topographic image of the rubbed PI-coated Si substrate and (b) its height profile. The scale bare is 2 μm.